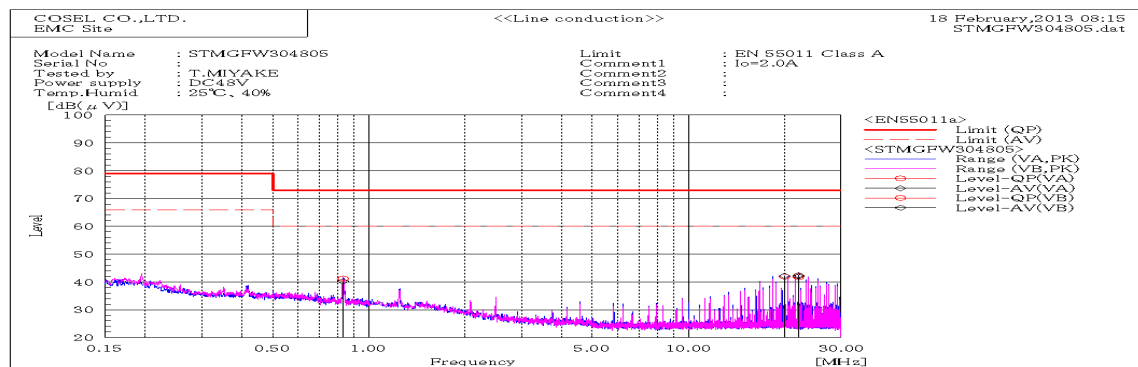
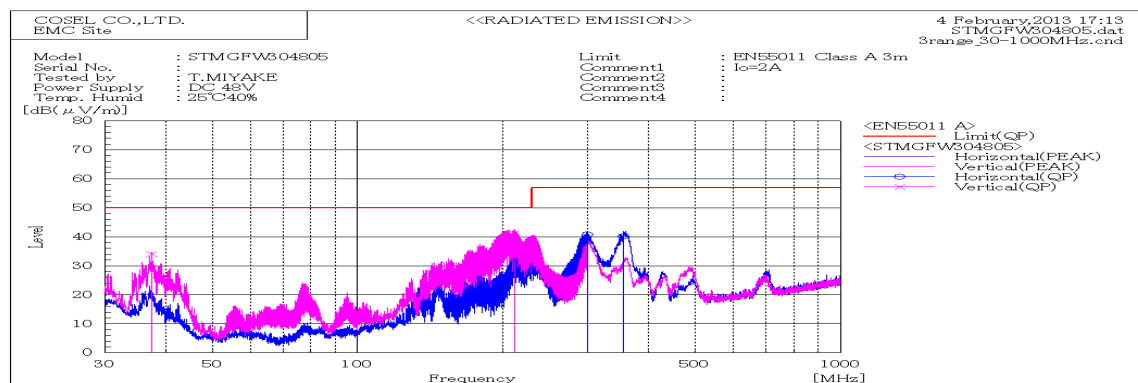


DATA SHEET

Model	STMGFW304805	Date	18-Feb-13
Test	EMI Line conduction & Radiated emission	Temp.	25 degreeC
		Humid.	40 %RH
		Tested by	T.Miyake



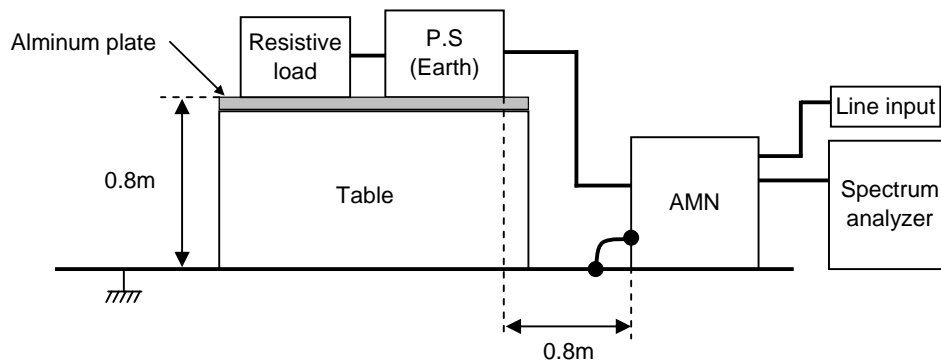
Frequency MHz	Harm	Line Phase	Reading dB(uV)		Factor dB	Level dB(uV)		Limit dB(uV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.83116		VA	21.1	20.1	20.1	41.2	40.2	73	60	31.8	19.8	Pass	
19.9601		VA	20.7	20.9	21.2	41.9	42.1	73	60	31.1	17.9	Pass	
22.0387		VB	20.6	20.8	21.1	41.7	41.9	73	60	31.3	18.1	Pass	
22.03685		VA	21.1	21.3	21.1	42.2	42.4	73	60	30.8	17.6	Pass	



Frequency MHz	Polarization	Stability	Reading dB(uV)		Space Loss dB	Level dB(mW)		Limit dB(mW)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	AV		QP	AV						
37.5	V	Stable	49.4	-15.4	34	50	16	50	16	Pass	105	11	
211.279	V	Stable	56.9	-15.6	41.3	50	8.7	50	8.7	Pass	126	172	
299.196	H	Stable	58.4	-17.6	40.8	57	16.2	57	16.2	Pass	102	74	
355.458	H	Stable	53.3	-13.1	40.2	57	16.8	57	16.8	Pass	113	86	

DATA SHEET		Date	18-Feb-13
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Miyake

1. Line conduction



2. Radiated emission

